

IN THE CLAIMS

Please amend the claims as follows. All the claims as amended are set forth.

1-30. (canceled)

31. (new) A clocking apparatus for an electronic tester, comprising:

a fixed frequency clock generator that generates a first clock;

a variable frequency clock generator that receives as an input the first clock from the fixed frequency clock generator and that generates a second clock;

a first high speed clock generator coupled to a digital pattern generator for digital testing of a device under test, wherein the first high speed clock generator receives as an input the second clock from the variable frequency clock generator and generates a third clock having a frequency that is a first multiple of a frequency of the second clock, wherein the third clock is supplied to the digital pattern generator;

a second high speed clock generator coupled to a sequenced measure system for analog testing of the device under test, wherein the second high speed clock generator receives as an input the first clock from the fixed frequency clock generator and generates a fourth clock having a frequency that is a second multiple of a frequency of the first clock, wherein the fourth clock is supplied to the sequenced measure system.

32. (new) The clocking apparatus of claim 31, further comprising a computer that sets a frequency of the second clock of the variable frequency clock generator in response to user input with respect to the computer.

33. (new) The clocking apparatus of claim 31, wherein the first multiple is less than one and the second multiple is greater than one.

34. (new) The clocking apparatus of claim 31, wherein the first and second multiples are each greater than one.